Disorder/order phase transition in C_{60} thin films studied by surface photovoltage spectroscopy

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The electronic properties of C_{60} thin films have been studied using surface photovoltage (SPV) spectroscopy at 120–300 K. Temperature variations of the SPV spectra are correlated with temperature-dependent x-ray diffraction patterns of the same samples, which indicate the first-order phase transition at $T_c = 250$ K. Absolute values of both the band-to-band and band (or band tail) -to-band tail SPV signals are shown to exhibit a clear minimum at $T_c = 250$ K in contrast with the well-known increasing background of the SPV intensity with decreasing temperature. The energy positions of the thresholds of the band-to-band and band (or band tail) -to-band tail regions in the SPV spectra also exhibit nonmonotonic behavior with a mirror symmetry and distinct extrema near T_c . On the basis of the presented results, we discuss possible reasons behind the effect of rotational and orientational states of C_{60} molecules on the electronic structure of the C_{60} fullerite and charge carrier transport in C_{60} thin films. © 2003 American Institute of Physics. [DOI: 10.1063/1.1625083]

I. INTRODUCTION

Solid C₆₀ is a molecular crystal with C₆₀ molecules occupying the lattice sites of a face-centered-cubic (fcc) structure¹ with the basic central intermolecular forces being of predominantly van der Waals nature.² Near the critical temperature $T_c = 250 - 260$ K, the C₆₀ crystal is known to undergo a first-order phase transition associated with changes in molecular rotations. Above T_c , C_{60} molecules rotate almost freely and therefore are equivalent, thus resulting in a fcc structure. Below T_c , the molecular rotations are partially locked with the fivefold symmetry axes having specific orientations. As a result, the molecules stay in their positions but acquire four different orientations, and the fcc structure transforms into a Pa3 structure with four interpenetrating simple cubic (sc) sublattices.³ Now, the average anisotropic forces are nonzero and negative, which corresponds to an extra constricting force and which thus results in a negative (upon cooling) jump in the lattice parameter.^{1,3} Free rotations above T_c provide a dynamic disorder but ensure the least possible orientation-related static disorder. On the contrary, below T_c the orientations are (at least partially) ordered, however, the presence of unequivalent mutual orientations of adjacent C₆₀ molecules entails an extra static disorder.

The relation between the rotational state of the molecules and electronic transport in solid C₆₀, and in particular its conductivity and photoconductivity near T_c , have recently become of great interest. The published data on C_{60} single crystals⁴⁻⁶ consistently report a sharp increase in conductivity, over a narrow range of about 0.4 K, when the temperature is lowered through T_c . These results were explained by the corresponding jumps (~ 1.5 times) in the charge carrier mobility at T_c .⁷ However, very recently, sharp changes in conductivity, near T_c , by an order of magnitude⁸ or even 4-5 orders of magnitude⁹ have been reported for highly crystalline C₆₀ films. These results have been interpreted in terms of trap-controlled mobility of the dominant charge carriers so that the temperature-related changes in the conductivity are attributed to variations in the concentration, energy distribution, and population of the carrier traps around the phase transition.⁸ Further insight into this phenomenon requires detailed study of the relationship between crystalline structure, orientational state and electronic structure of C_{60} films near T_c . In this article, we report results of joint analysis of the variation of x-ray diffraction (XRD) patterns and surface photovoltage (SPV) spectra of C₆₀ thin films with temperature.

SPV spectroscopy,^{10,11} which provides information on the electronic structure of semiconductors, has already proved to be efficient in studying C_{60} thin films.^{12,13} In particular, the SPV spectrum contains information on the band gap and the energy positions of the defect states in the gap.

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Formation of a SPV signal requires both photogeneration and transport of charge carriers. Therefore, SPV signals also reflect changes in mobility and lifetime of charge carriers.

II. EXPERIMENTAL DETAILS

 C_{60} thin films were deposited on a substrate of optical glass predeposited with an Ag layer using a vacuum deposition technique. The starting C_{60} powder (Super Gold Grade, >99.9%) was commercially obtained from Hoechst AG. The substrate temperature, the C_{60} deposition rate, and the thickness of the C_{60} films were of about 200 °C, 20 Å/s and 1000 Å, respectively. A detailed description of the deposition conditions was given elsewhere.¹⁴

The crystalline structure of the C_{60} films was characterized first at room temperature by powder XRD in Cu $K\alpha$ and Fe $K\alpha$ radiation, and subsequently by temperature-resolved XRD over the temperature range from 300 to 15 K. In the latter case, the XRD patterns also included reflections from a reference substance (high-purity copper). These reflections were utilized as a reference to reduce the error in the lattice parameter. The error in the lattice parameters thus did not exceed $\pm 0.02\%$. The sample temperature was measured with a platinum resistance thermometer, keeping the temperature stable at every measurement within ± 0.05 K. Morphology of the front surface of the films was studied by atomic force microscopy (AFM).

The SPV spectra were measured over the temperature range of 300–120 K, using a commercial Kelvin probe (Besocke Delta Phi, Jülich, Germany) with a sensitivity of ~ 1 mV, and a gas flow helium cryostat. Carrier generation was provided by light source and 0.25 m single monochromator (Oriel). Light intensity was adjusted using neutral density filters. Prior to the SPV measurements, the samples were kept in the dark, in air, and at room temperature. After being mounted in the cryostat they were annealed *in situ* in a vacuum of 10^{-3} Torr at 150 °C for 2 h. This treatment ensured the removal of most of oxygen from the sample.⁴

III. RESULTS AND DISCUSSION

Room-temperature XRD revealed that the C_{60} films have fcc polycrystalline structure with a strong $\langle 111 \rangle$ texture. Their room-temperature XRD patterns are the same as that shown in Fig. 2(a) in Ref. 14 and consist only of a very narrow and intensive (111) peak and its higher harmonics (222) and (333).

Figure 1 shows results of two sets of the temperatureresolved XRD measurements of the lattice parameter, a, in a typical C₆₀ sample. The second set of measurements was performed two days after the first one. We observed a welldefined discontinuity in the lattice parameter, $\Delta a/a$ = 0.06%, near the temperature T_c =250 K, which corresponds to the known disorder/order phase transition from the fcc to sc structure.³ The results of both sets of measurements almost coincide, except the very narrow vicinity of T_c . Note that in our films the critical temperature is lower and the change in the lattice parameter is smaller than in bulk C₆₀ samples, for which $T_c \approx 260$ K and $\Delta a/a = 0.32\%$.^{3,15,16} We have presented elsewhere¹⁷ XRD results on C₆₀ films of vari-



FIG. 1. Temperature dependence of the lattice parameter in a polycrystalline $\langle 111 \rangle$ -textured C₆₀ film determined by two sets of the temperature-resolved powder XRD data. The second XRD experiment was run two days after the first one. The solid line is a guide for the eye.

ous crystalline structure. A gradual reduction in $\Delta a/a$ and T_c with decreasing grain size in those samples has been demonstrated. This behavior, in comparison with single crystals, may originate from the relatively high density of structural defects (including grain boundaries), strain and impurities in thin films. In fact, it was previously shown that structural defects,¹⁸ impurities,¹⁸⁻²¹ strain,²² or an increased surface/ volume ratio²³⁻²⁵ can reduce the T_c value of solid C₆₀ by up to 30 K. The contribution of all these defects could suppress the discontinuity in *a* at the phase transition.^{19,21,24} It should be noted, however, that the changes in the orientational state of C₆₀ molecules occurring at the phase transition have a much stronger effect on the material's electronic properties than the discontinuity in the lattice parameter. In particular, we have demonstrated recently⁸ a strong effect of the phase transition on the conductivity and photoconductivity of a C_{60} film with coexisting amorphous and nanocrystalline phases for which no discontinuity in a was observed.

Figure 2 shows the SPV spectra measured at various temperatures for the same C_{60} film as in Fig. 1. In the SPV spectroscopy, information on the band gap and the energy



FIG. 2. SPV spectra for the polycrystalline $\langle 111 \rangle$ -textured C₆₀ film on an Ag predeposited glass substrate as measured at different temperatures in the range of 300–120 K.

positions of the defect states inside the gap is determined from changes in the spectral line slope that are caused by the photon assisted population or depopulation of electronic states.^{10,11} Accordingly, it is useful to distinguish three particular regions in measured spectra. To start with, we will determine these regions for the room-temperature spectrum. Excitation by photons with an energy of 0.8–1.6 eV defines region I. The sharp SPV signal with a negative slope is designated as the beginning of region II at approximately 1.65 eV that is characterized by a "knee" followed by some structure. The next region III with a clearly defined negative-slope signal starts at about 2.3 eV.

Region I is attributed to a subgap photoexcitation. Taking into account the results of photoemission and inverse photoemission room-temperature measurements of the band gap of C_{60} fullerite as of 2.3 eV,²⁶ the SPV signal in region III was previously^{12,13} attributed to a valence-to-conduction interband photoinduced excitation. The results of the combined experiment of photoconductivity, photoluminescence, photoinduced absorption excitation spectroscopy, resonant Raman spectroscopy, and electroabsorption,²⁷ and the comparative study of optical absorption and photoconductivity spectra,²⁸ confirmed that the main threshold in optical absorption and photoinduced carrier generation of C₆₀ films is at 2.3 eV. However, the authors of Refs. 27 and 28 attributed this signal to the lowest charge-transfer excitation state in solid C_{60} (formed by a Coulomb bound electron and hole located on different molecules) while the single-particle band gap of solid C_{60} is expected to be at 2.6 eV.

The origin of near-gap optical absorption and, in particular, of region II in the SPV spectra is still under discussion. The optical absorption of C_{60} thin films is known to extend from the gap energy forming a tail on the lower energy side.²⁹ A series of weak absorption structures have been observed in the tail of the optical and photoacoustical spectra.^{30,31} These structures have been ascribed to either exciton levels or the splitting due to vibronic modes of the molecules. Specifically, the absorption at 1.65 eV has been related to $h_u \rightarrow t_{1u}$ intramolecular excitation.^{32–34} It is well known that pristine solid C₆₀ exhibits semiconductor-like behavior in its optical absorption and electron transport properties and yet retains a molecular character. To describe the tail in optical absorption and, in particular, region II of the SPV spectra, we adopt an approach similar to that used in amorphous semiconductor physics.35 The corresponding simplified model of the electronic structure of C₆₀ fullerite including a room temperature mobility gap of about 2.3 eV, and a photoconduction gap of 1.6-1.7 eV has been recently suggested. The model and our arguments for the presence of tails of localized electronic states extending towards the forbidden gap as well as a discussion of the possible origins of the tails have been presented elsewhere.¹² In addition to the above-mentioned origins, a dynamic disorder (related to dynamics of C₆₀ molecular rotation, above T_c),^{12,36} and static orientational disorder, below T_c ,³⁷ have been suggested. It is obvious that the disorder/order phase transition must have an influence on these phenomena and, in turn, on both the SPV signal and the energy position of region II.



FIG. 3. Temperature dependence of the absolute value of the SPV signal change along the main knee in region II. The data have been obtained by processing of the SPV spectra presented in Fig. 2.

Regions II and III are present in all of the SPV spectra we measured on different C_{60} films.^{12,13,38} The negative slope of these signals indicates an *n* type of the conductivity of the C_{60} films. The SPV signal in region I may vary considerably depending on the crystalline structure and "history" of the film.^{12,13} This is consistent with similar behavior of the subgap optical absorption of C_{60} films.³⁹

Each of the above-mentioned regions (I, II and III) in the SPV spectra coincides with the corresponding well-defined features in the photoconductivity spectra of our samples⁴⁰ and the photoconductivity spectra reported by other groups.³⁶ In general,¹¹ the SPV signal may indicate a population/ depopulation of surface states or/and localized states in the bulk of the film near the surface. The clear correlation between the SPV spectra and such a bulk property as photoconductivity suggests that SPV spectroscopy is capable of scanning bulk electronic structure of C₆₀ films.

At room temperature the concentration of the deep states in the gap for the studied highly crystalline C_{60} film is too small to be detected by the method. This explains the absence of the sub-band-gap SPV response (in region I) at 300–270 K. However, starting from a certain temperature between 270 and 260 K a positive signal was observed in this region and its intensity increased with decreasing temperature.^{38,41,42}

Before going into details of the temperature variations of the main SPV signals (in regions II and III), we draw attention to their nonmonotonic character. To make this behavior apparent we plotted an absolute value of the signal change along the main knee in region II, ΔV_2 , as a function of temperature (Fig. 3). One can see a pronounced dip in the vicinity of the orientational phase transition with a clear minimum near $T_c = 250$ K against the natural growing background of the SPV intensity with temperature decreasing owing to the well known increased SPV sensitivity.¹¹ The signal in region III (not shown) exhibits a similar behavior. Critical behavior of the SPV signal near T_c qualitatively reproduces the temperature dependence of conductivity and photoconductivity in the corresponding temperature range recently observed for similar highly crystalline C₆₀ films⁸ and, therefore,



FIG. 4. Temperature dependence of the energy positions of the SPV signal onsets in regions II (a) and III (b). The data have been obtained by processing of the SPV spectra presented in Fig. 2 assuming that the positions of these onsets coincide with the minima in the negative derivative of the SPV curves in the corresponding spectral ranges.

may be explained by the effect of the phase transition on the electrical transport in the material.

SPV spectroscopy is very sensitive to any changes changes in the electronic structure, such as the band bending shape near a semiconductor's surface, the position of the Fermi level, etc. The effect of the phase transition on the electronic structure of C₆₀ films requires further systematic investigation. Here, we would like to demonstrate only one example of such an effect recorded by SPV spectroscopy. Figures 4(a) and 4(b) show the temperature dependence of the energy positions of the edges of regions II and III, E_2 and E_3 , respectively, as derived from Fig. 2. To be more quantitative, we assume that the positions of these edges coincide with the minima in the negative derivative of the SPV curves in the corresponding spectral ranges. According to our interpretation of the SPV signal in region II, a redshift of E_2 should indicate a broadening of the tails, and vice versa. Figure 4(a) demonstrates a general blueshift trend of E_2 with decreasing temperature below T_c (narrowing of the tails). This is consistent with the tail width behavior inferred previously from the temperature dependence of the optical transmission,^{39,43} deflection,³⁹ photothermal and photoconductivity^{43,44} spectra of C_{60} films and single crystals as well as with the general knowledge on the rotational states of C_{60} molecules in fullerite. Indeed, it is well known^{3,45} that below T_c the molecular rotations are partially locked with the fivefold symmetry axes C_5 having specific orientations. Even though the orientations $\langle 111 \rangle$ of the C₅ axes remain fixed, at temperatures below T_c down to roughly 90 K, the molecules execute turns around the threefold axes C₃ finishing every turn so that the same or another C5 is aligned along (111) direction. As a result, there are two slightly different mutual orientations of a pair of C_{60} molecules in the C_{60} solid. They differ in that in the more favorable one the closest electron-rich double bond of one molecule faces the electron deficient pentagon element of the other while in the less favorable orientation this double bond is opposite the electron-rich hexagon element of the other molecule. These mutual orientations are termed pentagonal and hexagonal, respectively. It is worth noting that free rotations above T_c provide a dynamic disorder but ensure the least possible orientation-related static disorder. On the contrary, below T_c the orientations are (at least partially) ordered, however, the presence of unequivalent mutual (hexagonal and pentagonal) orientations entails an extra static disorder. Since the pentagon to hexagon number ratio increases (from ~60% near 260 K to ~84% at 90 K),⁴⁵ and the frequency of the turns, decreases with temperature reduction, both the dynamic and static disorders should diminish with temperature reduction below T_c . This behavior may well explain the above-mentioned narrowing of the tail.

On the other hand, contrary to the above-mentioned results^{39,43,44} the redshift of E_2 (broadening of the tails) with decreasing temperature is in evidence just above T_c that manifests in the minimum in E_2 near $T_c = 250$ K. Meanwhile, the E_3 has a maximum near T_c [Fig. 4(b)]. The temperature dependencies of E_2 and E_3 demonstrate good mirror symmetry. Similar mirror symmetry has previously been demonstrated³⁹ for the temperature dependencies of the Tauc optical band gap46 of C60 films and the corresponding Urbach-tail width. The latter can be explained quite reasonably assuming that a redshift of the optical band gap occurs simultaneously with tail broadening. At the same time, the demonstrated temperature dependencies of the E_2 and E_3 onsets, and in particular their mirror symmetry, still need further experimental and theoretical clarification including a deeper insight into SPV formation mechanisms in C₆₀ fullerite and its dependence on the orientational state of this molecular crystal.

IV. CONCLUSIONS

We report nonmonotonic temperature variations in the SPV spectra of polycrystalline $\langle 111 \rangle$ -textured C₆₀ thin films in the vicinity of the first-order orientational phase transition at $T_c = 250$ K, as recorded by XRD. Absolute values of both the band-to-band and band (or band tail) -to-band tail SPV signals are shown to exhibit a clear minimum at $T_c = 250 \text{ K}$ in contrast to the well-known growing background of the SPV intensity with decreasing temperature. The temperature dependence of the intensities of these SPV signals near T_c qualitatively reproduces the temperature dependence of conductivity and photoconductivity in the corresponding temperature range recently observed for similar highly crystalline C_{60} films and, therefore, may be attributed to the effect of the phase transition on the electrical transport in the material. In addition, the energy positions of the thresholds of the band-to-band and band (or band tail) -to-band tail regions in the SPV spectra also exhibit a critical behavior with a mirror symmetry and distinct extrema near T_c . Such behavior manifests the effect of the phase transition on the electronic structure of the C₆₀ fulleride. In particular, the observed narrowing of the tails of localized electronic states with decreasing temperature below T_c is discussed in terms of the reduction of both the dynamic and static disorders in this molecular crystal due to changes in the orientational state of C_{60} molecules.

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- ¹R. Tycko, G. Dabbagh, R. M. Fleming, R. C. Haddon, A. V. Makhia, and S. M. Zahurak, Phys. Rev. Lett. 67, 1886 (1991).
- ²J. P. Lu, X.-P. Li, and R. M. Martin, Phys. Rev. Lett. 68, 1551 (1992).
- ³P. A. Heiney, J. E. Fisher, A. R. McGhhie, W. J. Romanow, A. M. Denestejn, J. P. McCauley, Jr., A. B. Smith III, and D. E. Cox, Phys. Rev. Lett. **66**, 2911 (1991).
- ⁴T. Arai, Y. Muracami, H. Suematsu, K. Kikuchi, Y. Ashiba, and I. Ikemoto, Solid State Commun. **84**, 827 (1992).
- ⁵D. Barancok, M. Haluska, V. Nadazdy, and J. Vajda, Solid State Commun. **94**, 597 (1995).
- ⁶K. C. Chiu, J. S. Wang, Y. T. Dai, and Y. F. Chen, Appl. Phys. Lett. **69**, 2665 (1996).
- ⁷E. Frankevich, Y. Maruyama, and H. Ogata, Chem. Phys. Lett. **214**, 39 (1993).
- ⁸E. A. Katz, D. Faiman, K. Iakoubovskii, A. Isakina, K. A. Yagotintsev, M. A. Strzhemechny, and I. Balberg, J. Appl. Phys. **93**, 3401 (2003).
- ⁹K.-C. Chiu, Y.-C. Su, R.-S. Chen, Y.-J. Lin, W.-R. Cheng, and S.-J. Tang, Jpn. J. Appl. Phys., Part 1 **41**, 6028 (2002).
- ¹⁰C. L. Balestra, J. Lagowski, and H. C. Gatos, Surf. Sci. 26, 317 (1971).
- ¹¹L. Kronik and Y. Shapira, Surf. Sci. Rep. **37**, 1 (1999).
- ¹²B. Mishori, E. A. Katz, D. Faiman, and Y. Shapira, Solid State Commun. 102, 489 (1997).
- ¹³E. A. Katz, D. Faiman, B. Mishori, Yoram Shapira, A. I. Shames, S. Shtutina, and S. Goren, J. Appl. Phys. 84, 3333 (1998).
- ¹⁴E. A. Katz, D. Faiman, S. Shtutina, and A. Isakina, Thin Solid Films **368**, 49 (2000).
- ¹⁵H. Kasatani, H. Terauchi, Y. Hamanaka, and S. Nakashima, Phys. Rev. B **47**, 4022 (1993).
- ¹⁶S. Fomenko, V. D. Natsik, S. V. Lubenets, V. G. Lirtsman, N. A. Aksenova, A. P. Isakina, A. I. Prokhvatilov, M. A. Strzhemechny, and R. S. Ruoff, Fiz. Nizk. Temp. **21**, 465 (1995); [Low Temp. Phys. **21**, 364 (1995)].
- ¹⁷E. A. Katz, D. Faiman, S. Shtutina, A. Isakina, and K. A. Yagotintsev, Mater. Res. Soc. Symp. Proc. 675, W7.6.1 (2001).
- ¹⁸N. A. Aksenova, A. P. Isakina, A. I. Prokhvatilov, M. A. Strzhemechny, and V. N. Varyukhin, in *Recent Advances in the Chemistry and Physics of Fullerenes and Related Materials*, edited by K. M. Kadish and R. S. Ruoff (The Electrochemical Society, Pennington, 1994), PV94–24, 1543 (1994).
- ¹⁹K. Matsuishi, K. Tada, S. Onari, and T. Arai, Philos. Mag. B **70**, 795 (1994).
- ²⁰ F. Yan, Ye-N. Wang, and M. Gu, J. Phys.: Condens. Matter **10**, 6875 (1998).

- ²¹ X. Li, Y. J. Tang, H. W. Zhao, W. S. Zhan, H. Wang, and J. G. Hou, Appl. Phys. Lett. **77**, 984 (2000).
- ²² Y. Yoneda, K. Sakaue, and T. Terauchi, J. Phys.: Condens. Matter 9, 2851 (1997).
- ²³ A. Glebov, V. Senz, J. P. Toennies, and G. Gensterblum, J. Appl. Phys. 82, 2359 (1997).
- ²⁴ A. Fartash, Phys. Rev. B 54, 17215 (1996).
- ²⁵A. Goldoni, C. Cepek, and S. Modesti, Phys. Rev. B 54, 2890 (1996).
- ²⁶ R. W. Lof, M. A. van Veenendaal, B. Koopmans, H. T. Jonkman, and G. A. Sawatzky, Phys. Rev. Lett. **68**, 3924 (1992).
- ²⁷ X. Wei, D. Dick, S. A. Jeglinski, and Z. V. Vardeny, Synth. Met. 86, 2317 (1997).
- ²⁸ R. Konenkamp, G. Priebe, and B. Pietzak, Phys. Rev. B **60**, 11804 (1999).
- ²⁹A. Skumanich, Chem. Phys. Lett. **182**, 486 (1991).
- ³⁰C. Reber, Y. Lee, J. McKiernan, J. I. Zink, R. S. Williams, W. M. Tong, D. A. A. Ohlberg, R. L. Whetten, and F. Diederich, J. Phys. Chem. **95**, 2127 (1991).
- ³¹S. Matsuura, T. Tsuzuki, T. Ishiguro, H. Endo, K. Kikuchi, Y. Achiba, and I. Ikemoto, J. Phys. Chem. Solids 55, 835 (1994).
- ³²R. R. Hung and J. J. Grabovski, J. Phys. Chem. **95**, 6073 (1991).
- ³³ M. Terazima, N. Hirota, H. Shinohara, and Y. Saito, J. Phys. Chem. 95, 9080 (1991).
- ³⁴C. Wen, T. Aida, I. Homna, H. Komiyama, and K. Yamada, J. Phys.: Condens. Matter 6, 1603 (1994).
- ³⁵N. F. Mott and E. A. Davis, *Electronic Processes in Noncrystalline Materials* (Clarendon, Oxford, 1979).
- ³⁶A. Hamed, in Organic Conductive Molecules and Polymers, edited by H. S. Nalwa (Wiley, Sussex, 1997), p. 486.
- ³⁷M. P. Gelfand and J. P. Lu, Phys. Rev. Lett. 68, 1050 (1992).
- ³⁸E. A. Katz, D. Faiman, S. Shtutina, A. Shames, S. Goren, B. Mishori, and Y. Shapira, Mater. Res. Soc. Symp. Proc. 485, 113 (1998).
- ³⁹T. Gotoh, S. Nonomura, H. Watanabe, and S. Goto, Phys. Rev. B 58, 10060 (1996).
- ⁴⁰E. A. Katz, D. Faiman, K. Iakoubovskii, A. Bozhko, and I. Balberg, in Proceedings of the 24th International Conference on the Physics of Semiconductors, Jerusalem, 2–7 August, edited by D. Gershoni (World Scientific, Singapore, 1999), CD-RDM.
- ⁴¹ The sub-band-gap SPV signal has a positive sign and, at low temperatures, may be even stronger than the main C_{60} super-band-gap SPV signals. Therefore, we tend to conclude that this signal originates from the back C_{60} /Ag interface (for detailed argumentation see Refs. 38 and 42). We believe that the increase of this signal with temperature reduction is caused by filling of interface states by electrons with the reduction of temperature.
- ⁴²E. A. Katz, D. Faiman, S. Shtutina, B. Mishori, and Y. Shapira, AIP Conf. Proc. 442, 527 (1998).
- ⁴³K.-C. Chiu, J.-S. Wang, and Y.-J. Lin, J. Appl. Phys. 79, 1784 (1996).
- ⁴⁴ R. Könenkamp, J. Erxmeyer, and A. Weidinger, Appl. Phys. Lett. 65, 758 (1994).
- ⁴⁵ W. I. F. David, R. M. Ibberson, T. J. S. Dennis, J. P. Hare, and K. Prassides, Europhys. Lett. 18, 219 (1992).
- ⁴⁶G. D. Cody, Semicond. Semimetals **21**, 11 (1984).